Welcome to the IEEE SW Test Workshop

June 8 to 11, 2008
San Diego, CA USA

Jerry Broz, Ph.D.
General Chair
IEEE SW Test Workshop
18th Annual SWTW

Paradise Point and Spa, San Diego, CA

You Are Here!
IEEE SW-Test Workshop

• SW Test IS a Probe Technology Forum …
  – It is "THE" Conference for Wafer Test Professionals
  – Practical solutions to real problems
  – A balance mixture of semiconductor manufacturer and supplier presentations

• Informal Conference …
  – Great social activities and informal discussions
  – Meet new people and have a little fun!
IEEE SW-Test Workshop

• Sponsored by the IEEE Components, Packaging and Manufacturing Technology (CPMT) Society

• Leading international forum for scientists and engineers engaged in the research, design and development of revolutionary advances in micro-systems packaging and manufacture.
What’s New for 2008?

• Record Number of Submissions …
  – 9 Technical Sessions
    • Total of 31 Podium Presentations
  – 2 Poster Sessions
    • Total of 10 Poster Presentations

• Products / Services EXPO – 2008
  – Expanded to 52 full size booths
  – SOLD OUT ! (… thanks ! …)
Corporate Supporter Program

- BucklingBeam
- FEINMETALL
- international TEST SOLUTIONS
- CASCADE® MICROTECH
- FormFactor
- MICRONICS JAPAN CO., LTD.
- hyphenated systems, llc
- RUDOLPH TECHNOLOGIES

June 8 to 11, 2008
“How’s My Driving?”

• Organization and Technical Program …
  – Jerry Broz, Ph.D., International Test Solutions, General Chair
  – William Mann, Chair Emeritus and Social Coordinator
  – Brett Crump, Micron Technology, Program Chair
  – Maddie Harwood, CEM Inc, Registration and Finance Chair
  – Meredith Griffith, CEM Inc., Exhibits / Registration Coordinator

Program Committee and Steering Committee

• Ken Karklin, Touchdown Technologies
• Patrick Mui, JEM America
• Roger Sinsheimer, Xandex
• Fred Taber, BiTS Workshop
  – Proceedings Coordinator
• Warren “Stu” Crippen, Intel

• Nadine Aldahhan, Freescale
• Jack Courtney, IBM
• Ger Koch, NXP Semiconductor
• Michael Egloff, AMD
• Michael Harris, Texas Instruments
• Rey Rincon, Consultant
Technical Program / Agenda

- Sunday, June 8, 2008
  - Tutorial w/ 3 presentations
  - Registration and Cocktails
  - Dinner
  - Probe Year In Review
  - Keynote …

“Wafer Test Industries Impact on ATE”
Debbora Ahlgren
Vice President & Chief Marketing Officer
Verigy, Inc.
Technical Program / Agenda

• Monday, June 9
  – Continental Breakfast
  – MEMS for Production-Level Probing
  – Advances in Traditional Probe Card Technologies
  – Lunch
  – Improving Test Cell Performance
  – Power and High Voltage
  – Exhibits Open From 5:00 to 8:00 PM
    • Carving stations and hors d’oeuvres served
  – Vendor “Press Time” / Sponsored Events
  – Socializing at the Barefoot Bar
Technical Program / Agenda

• Tuesday, June 10
  – Continental Breakfast
  – Large Array Probing
  – Probe Potpourri
  – Lunch (Outdoor, weather permitting, Lawn BBQ)
  – Probe Card Cleaning Practices
  – Exhibits Open from 3:00 to 5:00 PM
  – Two Technical Poster Sessions
    • Session 01 - 3:00 to 3:30 PM
    • Session 02 - 3:30 to 4:00 PM
  – Midway Museum for reception, dinner, tours
    • Buses depart for Midway Museum at 6:00PM
Tuesday Social

- Relaxed networking
- Private Reception and Buffet Dinner
- Tours, Simulators, FUN!
Technical Program / Agenda

• Wednesday, June 11
  – Continental Breakfast
  – Strategic Design Methodologies
  – Probe Challenges
  – Best Presentations Awards
  – Adjournment and Lunch
Recognition & Awards

• Best Overall Presentation
• Best Data Presented
• Most “Inspirational” Presentation
• Best Presentation, Tutorial in Nature

• Other “Special Awards”
SWTW-2007 Awards

Best Overall Presentation
"ROUTE60™ : A New Vertical Probing Technology"

Roberto Crippa
Stefano Lazzari
Technoprobe, S.p.A

Raffaele Vallauri
Massimo Gervasoni
STMicroelectronics

Best Data Presentation
"Electrical Contact Resistance - The Key Parameter in Probe Card Performance"

January Kister
Steve Hopkins
Microprobe, Inc.
Most Inspirational Presentation
“Thin Film Interposer Probes in Production”
Chris Sullivan
John Hagios
Steve Duda
Sally Francis
IBM Microelectronics

Best Presentation, Tutorial in Nature
“Taguchi's Method for Probe Card Development”
Vincent Reynaud
Mesatronics
Best Poster Presentation

“Design Considerations for Parametric-RF Probing in Production Test Environments”

Roger Hayward
Bob Hansen
Cascade MicroTech

Lifetime Achievement Award

Presented to …

William Mann
SW-Test Workshop
Founder and Chair Emeritus
The “Special” Award

“What A Load Of Crap !”

For the Poorest Disguised Sales Pitch

“What happens at SWTW stays at SWTW !”
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<th>Exhibitor Name</th>
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Don’t Get Lost!

- Buses to Midway Museum
- Exhibits
- Posters
- Conference
Don’t Get Lost in Paradise!
http://www.swtest.org

• Central Online Repository
  – Past presentations
  – Online registration
  – Most current news for SW Test Workshop
  – Sign up for our mailing list

• Tremendous continued success !!
  – Over 115K visits!
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  Mesa, Arizona

- **IS-Test Workshop**
  Freising, Germany

- **Global STC Conference**
  San Diego, California

- **Electronic Components and Technology Conference**
  Orlando, Florida